

A M E N D M E N T

IN THE SPECIFICATION:

Please amend the title wherever it appears as follows:

METHODS AND APPARATUS FOR ~~DEFECT ISOLATION~~ TESTING A
SCAN CHAIN TO ISOLATE DEFECTS

Please amend the abstract as follows:

~~In a first aspect, a first method is~~ Systems, methods
and apparatus are provided for isolating a defect in a scan
chain. The first method invention includes the steps of (1)
modifying a first test mode of one or more of a plurality of
latches included in the a scan chain, ~~(2) operating the one or~~
~~more latches whose first test modes are modified in the modified~~
~~first test mode,~~ and (3) operating one or more of the plurality
of latches included in the scan chain in a second test mode. A
portion of the scan chain adjacent and following a stuck-at-0 or
stuck-at-1 fault in the scan chain may store and/or output a
value complementary to the value on the output of the previous
portion of the scan chain due to the fault. Such values may be
unloaded from the scan chain and used for diagnosing (e.g.,
isolating a defect in) the defective scan chain. Numerous other
aspects are provided.